

## RELIABILITY/QUALIFICATION SUMMARY:

Qualification and reliability data will be available upon request.

## CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.
IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

| Customer: | $\square \quad$ Approval for shipments prior to effective date. |
| :---: | :---: |
| Name/Date: | E-Mail Address: |
| Title: | Phone\#/Fax\# : |
| CUSTOMER COMMENTS: |  |
|  |  |
| IDT ACKNOWLEDGMENT OF RECEIPT: |  |
| RECD. BY: | DATE: |

## PRODUCT/PROCESS CHANGE NOTICE (PCN) ADDENDUM

## PCN Summary

 PCN Type:Design Change Change to Fab Process

Commodity
Logic
Forecast or Execute
Execute
Planned or Unplanned
Unplanned
Data Sheet Change
No Change

## Detail of Change

For selected 3.3V Double Density Logic FCT products, IDT will be migrating to a new die revision for process consolidation. There is no data sheet specification or package change.

The affected part numbers are: 54/74FCT163344, 163501, 163827, 163646, 163244, 163245,
74FCT163373, 163374, 163543, 163601 and 163952

Process / Design Changes

## Current Die <br> Replacment Die

| 54/74FCT163344 | $54 / 74 \mathrm{FCT} 163646$ |
| :--- | :--- |
| 54/74FCT163501 | $54 / 74 \mathrm{FCT} 163244$ |
| 54/74FCT163827 | 54/74FCT163245 |
| 74FCT163543 | 74FCT163373 |
| 74FCT163601 | 74FCT163374 |
| 74FCT163952 |  |

Wafer Fab Technology
Feature Size
Minimum Gate Oxide
Wafer Size
Die Dimension (sq mils)
Fab Facility
Datecode Prefix Designator

CMOS 7
$0.8 \mu \mathrm{~m}$
140 Å
6"
11.4

Fab 2
N

CMOS 7
$0.8 \mu \mathrm{~m}$
140 Å
$6 "$
6.28

Fab 2
L

CMOS 8
$0.6 \mu \mathrm{~m}$
$140 \AA$
6"
7.76

Fab 2
X

## Conversion schedule (Estimated)

PCN \# L9910-03R1

## Sample Availability

$\underline{\text { Production Shipments }}$
Available
February 1, 2000
54/74FCT163501
Available
February 1, 2000

## PRODUCT/PROCESS CHANGE NOTICE (PCN) ADDENDUM

54/74FCT163646<br>54/74FCT163827<br>54/74FCT163244<br>54/74FCT163245<br>74FCT163373<br>74FCT163374<br>74FCT163543<br>74FCT163601<br>74FCT163952

Available
Available
Available
Available
Available
Available
Available
Available
Available

February 1, 2000
February 1, 2000
February 1, 2000
February 1, 2000
June 22, 2000
June 22, 2000
June 22, 2000
June 22, 2000
June 22, 2000

## Qualification Data

Test Vehicle: 65501X/65373X/65244X/65646X

|  | Lot \#1 | Lot \#2 | Lot \#3 |
| :--- | :---: | :---: | :---: |
| Operating Life Test (Dynamic) <br> $\left(1000\right.$ Hrs @ $\left.125^{\circ} \mathrm{C}, \mathrm{Vcc}=3.3 \mathrm{~V}\right)$ | $116 / 0$ | $116 / 0$ | $116 / 0$ |
| Temperature cycling <br> $\left(-65^{\circ} \mathrm{C}\right.$ to $\left.+150^{\circ} \mathrm{C}, 500 \mathrm{cyc}\right)$ | $45 / 0$ | $45 / 0$ | $45 / 0$ |
| Bake and Ball Shear Test | $20 / 0$ | $20 / 0$ | $20 / 0$ |
| Die Shear Test | $3 / 0$ | $3 / 0$ | $3 / 0$ |
| ESD: HMB Category II (>2kV) Mil-Std 883, Method 3015 | $3 / 0$ | $3 / 0$ | $3 / 0$ |
| ESD: CDM | $3 / 0$ | $3 / 0$ | $3 / 0$ |
| Latch-up JEDEC Std 17 | $10 / 0$ | N/A | N/A |
| Electrical characterization | $10 / 0$ | N/A | N/A |
| I/O capacitance | $5 / 0$ | N/A | N/A |

## Characterization Data:

Characterization Data is available upon request.

